

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp	
L1	7939	filter\$3 with trap\$1	USPAT	OR	OFF	2005/07/29 10:39	
L2	708	1 and (semiconductor wafer)	USPAT	OR	OFF	2005/07/29 10:38	
L3	1403	filter\$3 with (trap\$1:screen mesh) with (height mm millimeter)	USPAT	OR	OFF	2005/07/29 10:56	
L4	36011	"dimethyl sulfoxide" DMSO	USPAT	OR	OFF	2005/07/29 10:57	
L5	2131	4 and ("dry film" photoresist etch\$3)	USPAT	OR	OFF	2005/07/29 10:57	
L6	9	5 AND SPS - (tradename)	USPAT	OR	OFF	2005/07/29 10:57	
L7	109	"stripping rate" "trapping rate"	EPO; JPO; DERWENT	OR	OFF	2005/07/29 11:03	
L8	9	L7 SAME (FILTER\$3 MESH SCREEN)	EPO; JPO; DERWENT	OR	OFF	2005/07/29 11:03	
S1	2	"5942369".pn. "4906341".pn.	USPAT	OR	OFF	2005/07/27 13:08	
S2	5	"6598314".pn. "6620722".pn. "6691738".pn. "6712260".pn. "6918397".pn.	USPAT	OR	OFF	2005/07/27 13:11	
S3	42	156/345:18	USPAT	OR	OFF	2005/07/27 13:18	
S4	137	156/345.15 156/345.11	USPAT	OR	OFF	2005/07/27 13:47	
S5	2043	(prefilter\$3 filter) same ("dry film" photoresist)	USPAT	OR	OFF	2005/07/27 13:26	
S6	1133	(prefilter\$3 filter) with ("dry film" photoresist)	USPAT	OR	OFF	2005/07/27 13:38	
Examiner assig See ▾	S7	216	macarthur-s\$.xa.	USPAT	OR	OFF	2005/07/27 13:38
	S8	3223	"Taiwan Semiconductor Manufacturing".as.	USPAT	OR	OFF	2005/07/27 13:48
exam er	S9	0	S8 and "dry film removal"	USPAT	OR	OFF	2005/07/27 13:48
	S10	22	S8 and "dry film"	USPAT	OR	OFF	2005/07/27 13:49
exam er	S11	1117	powell-william.xa. powell-william. xp.	USPAT	OR	OFF	2005/07/27 13:50
	S12	143	S11 and filter\$3	USPAT	OR	OFF	2005/07/27 13:51
exam er	S13	2583	stinson-f\$.xa. stinson-f\$.xp.	USPAT	OR	OFF	2005/07/27 13:51
	S14	804	S13 and filter\$3	USPAT	OR	OFF	2005/07/27 13:51
exam er	S15	947	S12 S14	USPAT	OR	OFF	2005/07/27 14:04
	S16	17035	134/26, "94.1", "95.1", "111" and "902."	USPAT	OR	OFF	2005/07/27 14:05
exam er	S17	4380	134/26, 134/94.1 134/95.1 134/111 134/902	USPAT	OR	OFF	2005/07/27 14:06
	S18	1855	S17 and ((pre adj filter\$3) or filter\$3)	USPAT	OR	OFF	2005/07/27 14:07
S19	718	S18 and (wafer:semiconductor)	USPAT	OR	OFF	2005/07/27 14:07	

S20	6167	trap\$4 and (dfr "dry film" photoresist)	USPAT	OR	OFF	2005/07/28 12:33
S21	521	trap\$4 same (dfr "dry film" photoresist)	USPAT	OR	OFF	2005/07/28 11:49
S22	196	trap\$4 with (dfr "dry film" photoresist)	USPAT	OR	OFF	2005/07/28 12:00
S23	6	(trap\$4 with filter\$3) with (dfr "dry film" photoresist)	USPAT	OR	OFF	2005/07/28 12:01
S24	35	(screen\$3 with filter\$3) with (dfr "dry film" photoresist)	USPAT	OR	OFF	2005/07/28 12:01
S25	40	S23 S24	USPAT	OR	OFF	2005/07/28 12:01
S26	13	S25 and (mm height millimeter)	USPAT	OR	OFF	2005/07/28 12:25
S27	2803	trap\$4 and (dfr "dry film" photoresist)	US-PPGPUB; JPO; DERWENT	OR	OFF	2005/07/28 12:36
S28	314	trap\$4 same(dfr "dry film" photoresist)	US-PPGPUB; JPO; DERWENT	OR	OFF	2005/07/28 12:36
S29	149	trap\$4 with (dfr "dry film" photoresist)	US-PPGPUB; JPO; DERWENT	OR	OFF	2005/07/28 12:50
S30	1	trap\$4 with (dfr "dry film" photoresist)with (height mm millimeter)	US-PPGPUB; JPO; DERWENT	OR	OFF	2005/07/28 14:45
S31	538	"stripping rate" "trapping rate"	US-PPGPUB; USPAT	OR	OFF	2005/07/28 12:55
S32	174	S31 and filter\$43.	US-PPGPUB; USPAT	OR	OFF	2005/07/28 12:52
S33	1	DMSO and TMAM	US-PPGPUB; USPAT	OR	OFF	2005/07/28 12:55
S34	15	SPS-200	US-PPGPUB; USPAT	OR	OFF	2005/07/28 12:53
S35	15	"SPS-200"	US-PPGPUB; USPAT	OR	OFF	2005/07/28 12:54
S36	0	"SPS-200"	EPO; JPO; DERWENT	OR	OFF	2005/07/28 12:55
S37	0	DMSO and TMAM	EPO; JPO; DERWENT	OR	OFF	2005/07/28 12:55
S38	109	"stripping rate" "trapping rate"	EPO; JPO; DERWENT	OR	OFF	2005/07/29 11:02
S39	947	trap\$4 near5 rate	US-PPGPUB; JPO; DERWENT	OR	OFF	2005/07/28 14:45
S40	2083	trap\$4 near5 rate	US-PPGPUB; USPAT	OR	OFF	2005/07/28 14:46

S41	1089	S40 and (filter\$3 screen\$3)	US-PGPUB; USPAT	OR	OFF	2005/07/28 14:46
S42	112	S41 and (df1 (dry near4 film) (photo adj2resist))	US-PGPUB; USPAT	OR	OFF	2005/07/28 14:47